Jun-01-04

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DATE:

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FILE NO:

AMAT/5262/CMP/CMP/RKK

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FROM:

Keith M. Tackett

PAGE(S) with cover:

2

ORIGINAL TO

FOLLOW?

☐ YES ⊠ NO

SECOND RESPONSE TO FINAL OFFICE ACTION DATED FEBRUARY 6, 2004

TITLE:

Method and Apparatus For Forming Metal Layers

U.S. SERIAL NO.:

09/961,134

FILING DATE:

September 21, 2001

INVENTOR:

Tsai, et al.

EXAMINER:

Edna Wong

GROUP ART UNIT:

1753

CONFIRMATION NO.:

4110

CONFIDENTIALITY NOTE

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Atty. Dkt. No. AMAT/S262/CMP/CMP/RKK

IN THE CLAIMS:

Jun-01-04

The status of the claims is as follows:

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1-23. (Cancelled)

24. (Previously Presented): A method of forming a metal layer on a substrate, comprising:

positioning a substrate in an electroplating cell having a porous pad and an electrolyte solution therein;

contacting at least a portion of the substrate to the porous pad;

forming a metal layer on the substrate by biasing the substrate relative to an electrode at a first electrical bias and then biasing the substrate relative to the electrode at a second electrical bias, wherein the first electrical bias deposits metal on the substrate and the second electrical bias removes metal from the substrate; and

varying the magnitude of the second electrical bias relative to the first electrical bias as the metal layer is formed.

25. (Cancelled)